

| Application/Control No. | Applicant(s)/Patent under Reexamination |
|-------------------------|-----------------------------------------|
| 10/577,854              | TAKEI ET AL.                            |
| Examiner                | Art Unit                                |
| <br>  Sin J. Lee        | 1795                                    |

|       | SEAR     | CHED |          |
|-------|----------|------|----------|
| Class | Subclass | Date | Examiner |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |
|       |          |      |          |

| INTERFERENCE SEARCHED |      |          |  |  |  |
|-----------------------|------|----------|--|--|--|
| bclass                | Date | Examiner |  |  |  |
|                       |      |          |  |  |  |
|                       |      |          |  |  |  |
|                       |      |          |  |  |  |
|                       |      |          |  |  |  |
|                       |      |          |  |  |  |
|                       |      |          |  |  |  |

| DATE  3/29/2009 | SJL |
|-----------------|-----|
| 3/29/2009       | SJL |
|                 |     |
|                 |     |
|                 |     |
|                 |     |
|                 |     |
|                 |     |
|                 |     |
|                 |     |
|                 |     |
|                 |     |